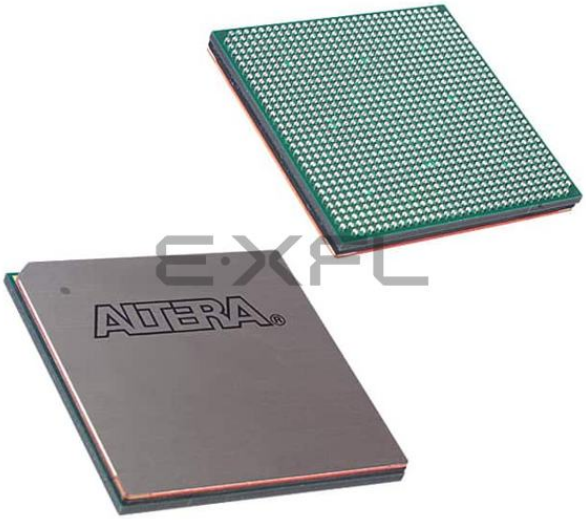

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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

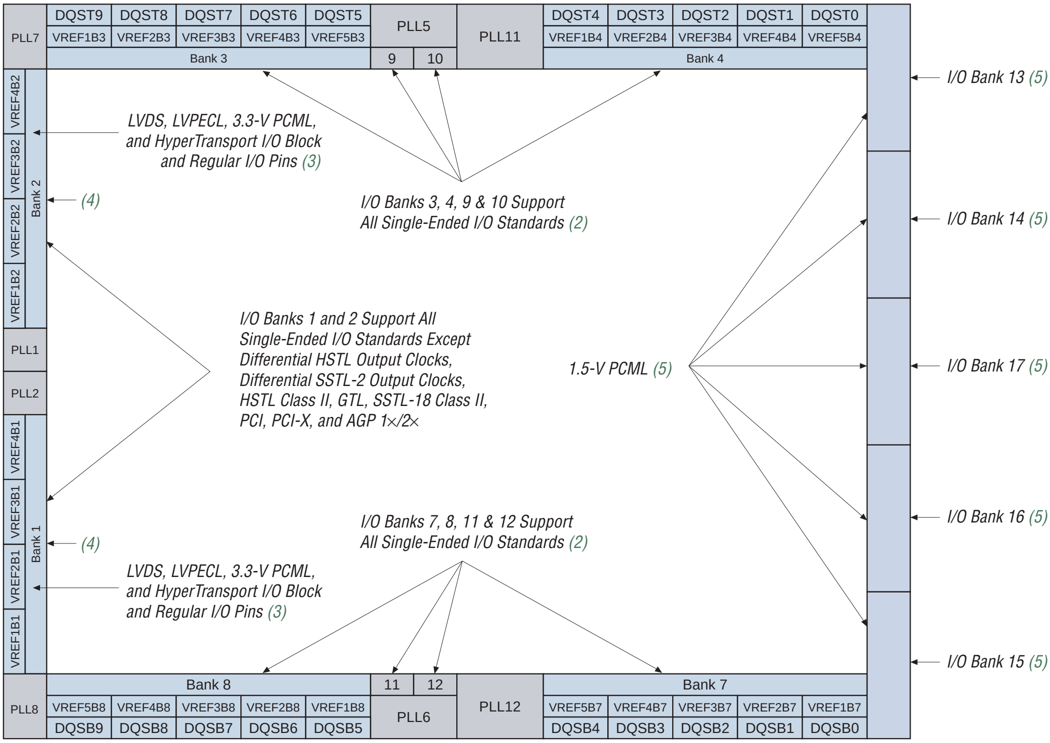
Details	
Product Status	Obsolete
Number of LABs/CLBs	4125
Number of Logic Elements/Cells	41250
Total RAM Bits	3423744
Number of I/O	624
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1020-BBGA
Supplier Device Package	1020-FBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1sgx40gf1020c6n

Revision History

The table below shows the revision history for Chapters 1 through 7.

Chapter(s)	Date / Version	Changes Made	Comments
1	February 2005, v1.0	Initial Release.	
2	June 2006, v1.1	● Updated "Serial Loopback" section. ● Updated Figures 2–1 through 2–3. ● Updated Figure 2–13. ● Updated Figures 2–26 and 2–27.	
	February 2005, v1.0	Initial Release.	
3	August 2005, v1.1	Added Note (3) to Figure 3-7.	
4	February 2005, v1.0	Initial Release.	
5	February 2005, v1.0	Initial Release.	
6	June 2006, v1.2	● Updated "Operating Conditions" section. ● Updated Table 6–4. ● Updated note 3 in Table 6–6. ● Added note 12 in Table 6–7. ● Updated Figure 6–1. ● Added Figure 6–2. ● Updated Tables 6–13 through 6–16.	● Changed V_{OD} to V_{ID} for receiver input voltage and `refclkb` input voltage in Table 6–4. ● Changed value for undershoot during transition from -0.5 V to -2.0 V in note 3 of Table 6–6. ● Changed value of V_{OCM} from mV to V in Table 6–15. ● Changed unit value of W to Ω.
	August 2005, v1.1	Updated Tables 6-7 and 6-50.	
7	February 2005, v1.0	Initial Release.	

Figure 1–1. Stratix GX I/O Blocks *Note (1)*



Notes to Figure 1–1:

(1) Figure 1–1 is a top view of the Stratix GX silicon die.
(2) Banks 9 through 12 are enhanced PLL external clock output banks.
(3) If the high-speed differential I/O pins are not used for high-speed differential signaling, they can support all of the I/O standards except HSTL class I and II, GTL, SSTL-18 Class II, PCI, PCI-X, and AGP 1×/2×.
(4) For guidelines for placing single-ended I/O pads next to differential I/O pads, see the *Selectable I/O Standards in Stratix & Stratix GX Devices* chapter of the *Stratix GX Device Handbook, Volume 2*.
(5) These I/O banks in Stratix GX devices also support the LVDS, LVPECL, and 3.3-V PCML I/O standards on reference clocks and receiver input pins (AC coupled).

FPGA Functional Description

Stratix GX devices contain a two-dimensional row- and column-based architecture to implement custom logic. A series of column and row interconnects of varying length and speed provide signal interconnects between logic array blocks (LABs), memory block structures, and DSP blocks.

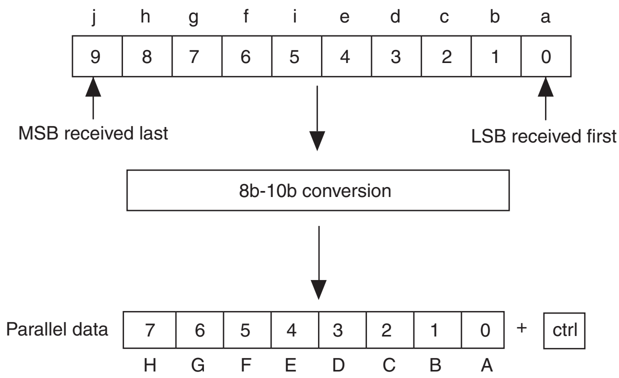
XAUI Mode

In XAUI mode, the rate matcher adheres to clause 48 of the IEEE 802.3ae specification for clock rate compensation. The rate matcher performs clock compensation on columns of `/R/` (`/K28.0/`), denoted by `//R//`. An `//R//` is added or deleted automatically based on the number of words in the FIFO buffer.

8B/10B Decoder

The 8B/10B decoder converts the 10-bit encoded code group into 8-bit data and 1 control bit. The 8B/10B decoder can be bypassed. The following is a diagram of the conversion from a 10-bit encoded code group into 8-bit data + 1-bit control.

Figure 2–20. 8B/10B Decoder Conversion

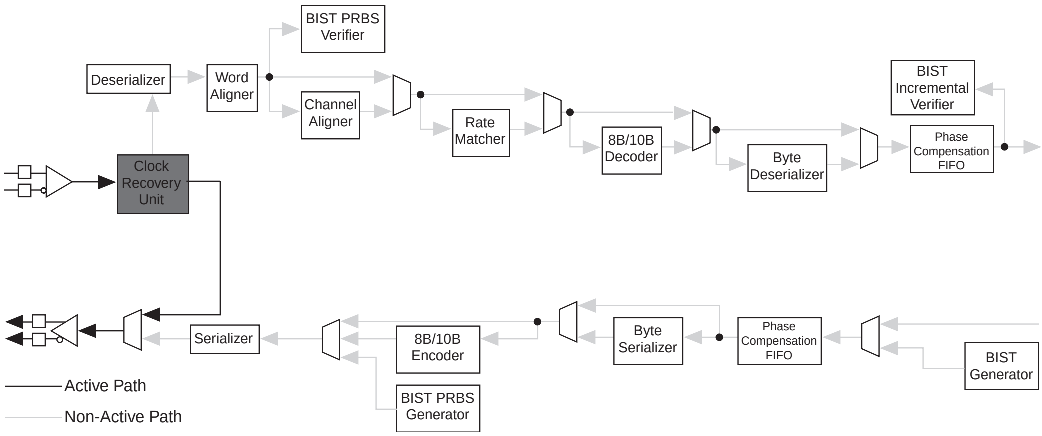


There are two optional error status ports available in the 8B/10B decoder, `rx_errdetect` and `rx_disperr`. Table 2–7 shows the values of the ports from a given error. These status signals are aligned with the code group in which the error occurred.

Table 2–7. Error Signal Values

Types of Errors	rx_errdetect	rx_disperr
No errors	1'b0	1'b0
Invalid code groups	1'b1	1'b0
Disparity errors	1'b1	1'b1

Figure 2–23. Data Path in Reverse Serial Loopback Mode



BIST (Built-In Self Test)

The Stratix GX transceiver has built-in self test modes to aid in debug and testing. The BIST modes are set in the Stratix GX MegaWizard Plug-In Manager in the Quartus II software. Only one BIST mode can be set for any single instance of the transceiver block. The BIST mode applies to all channels used in a transceiver.

The following is a list of the available BIST modes:

- PRBS generator and verifier
- Incremental mode generator and verifier
- High-frequency generator
- Low-frequency generator
- Mixed-frequency generator

Figures 2–24 and 2–25 are diagrams of the BIST PRBS data path and the BIST incremental data path, respectively.

Figure 2–24. BIST PRBS Data Path

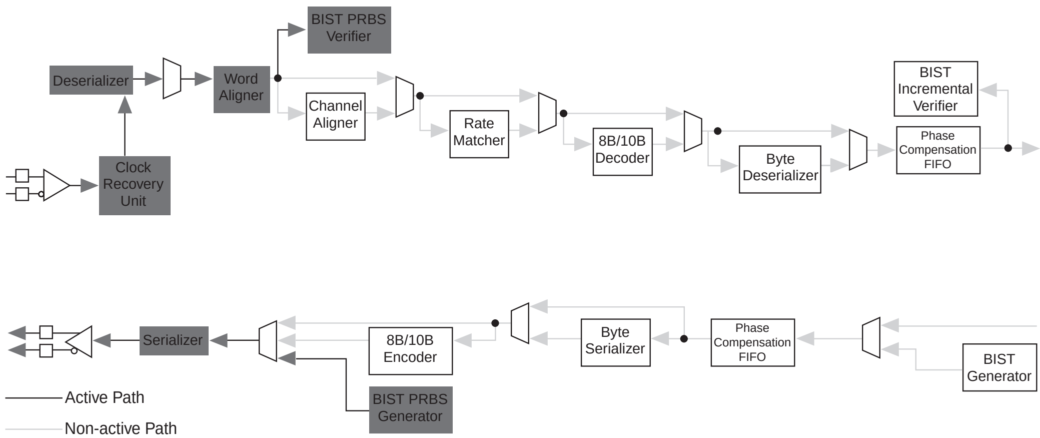


Figure 2–25. BIST Incremental Data Path

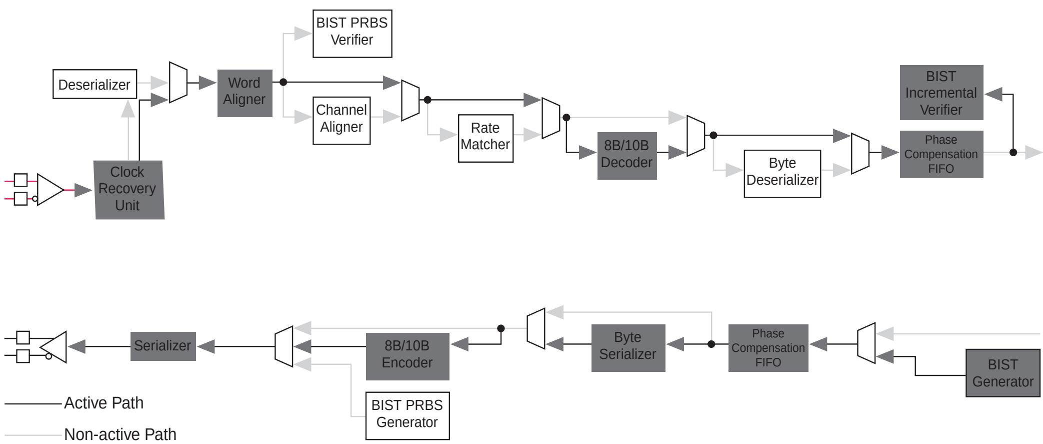


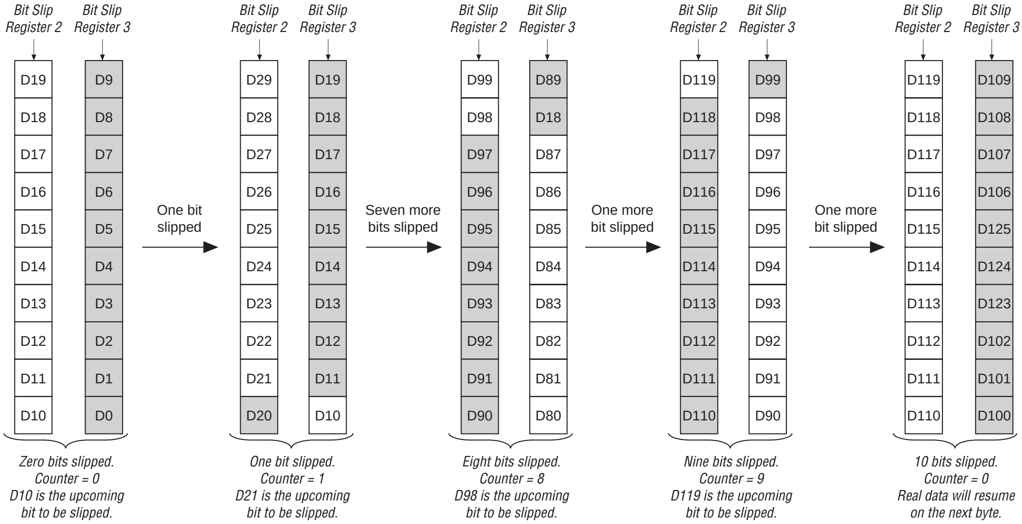
Table 2–9 shows the BIST data output and verifier alignment pattern.

Table 2–9. BIST Data Output & Verifier Alignment Pattern (Part 1 of 2)

BIST Mode	Output	Polynomials	Verifier Word Alignment Pattern
PRBS 8-bit	$2^8 - 1$	$x^8 + x^7 + x^5 + x^3 + 1$	1000000011111111
PRBS 10-bit	$2^{10} - 1$	$x^{10} + x^7 + 1$	1111111111

The DPA data-realignment circuitry allows further realignment beyond what the *J* multiplication factor allows. You can set the *J* multiplication factor to be 8 or 10. However, because data must be continuously clocked in on each low-speed clock cycle, the upcoming bit to be realigned and previous *n* –1 bits of data are selected each time the data realignment logic's counter passes *n* –1. At this point the data is selected entirely from bit-slip register 3 (see Figure 3–11) as the counter is reset to 0. The logic array receives a new valid byte of data on the next divided low speed clock cycle. Figure 3–11 shows the data realignment logic output selection from data in the data realignment register 2 and data realignment register 3 based on its current counter value upon continuous request of data slipping from the logic array.

Figure 3–11. DPA Data Realigner



Use the `rx_channel_data_align` signal within the device to activate the data realigner. You can use internal logic or an external pin to control the `rx_channel_data_align` signal. To ensure the rising edge of the `rx_channel_data_align` signal is latched into the control logic, the `rx_channel_data_align` signal should stay high for at least two low-frequency clock cycles.

LAB and do not drive directly to LAB local interconnects. R24 row interconnects drive LAB local interconnects via R4 and C4 interconnects. R24 interconnects can drive R24, R4, C16, and C4 interconnects.

The column interconnect operates similarly to the row interconnect and vertically routes signals to and from LABs, TriMatrix memory, DSP blocks, and IOEs. Each column of LABs is served by a dedicated column interconnect, which vertically routes signals to and from LABs, TriMatrix memory and DSP blocks, and horizontal IOEs. These column resources include:

- LUT chain interconnects within an LAB
- Register chain interconnects within an LAB
- C4 interconnects traversing a distance of four blocks in up and down direction
- C8 interconnects traversing a distance of eight blocks in up and down direction
- C16 column interconnects for high-speed vertical routing through the device

Stratix GX devices include an enhanced interconnect structure within LABs for routing LE output to LE input connections faster using LUT chain connections and register chain connections. The LUT chain connection allows the combinatorial output of an LE to directly drive the fast input of the LE right below it, bypassing the local interconnect. These resources can be used as a high-speed connection for wide fan-in functions from LE 1 to LE 10 in the same LAB. The register chain connection allows the register output of one LE to connect directly to the register input of the next LE in the LAB for fast shift registers. The Quartus II Compiler automatically takes advantage of these resources to improve utilization and performance. Figure 4–9 shows the LUT chain and register chain interconnects.

single block of RAM ideal for data packet storage. The different-sized blocks allow Stratix GX devices to efficiently support variable-sized memory in designs.

The Quartus II software automatically partitions the user-defined memory into the embedded memory blocks using the most efficient size combinations. You can also manually assign the memory to a specific block size or a mixture of block sizes.

M512 RAM Block

The M512 RAM block is a simple dual-port memory block and is useful for implementing small FIFO buffers, DSP, and clock domain transfer applications. Each block contains 576 RAM bits (including parity bits). M512 RAM blocks can be configured in the following modes:

- Simple dual-port RAM
- Single-port RAM
- FIFO
- ROM
- Shift register

When configured as RAM or ROM, you can use an initialization file to pre-load the memory contents.

The memory address depths and output widths can be configured as 512 × 1, 256 × 2, 128 × 4, 64 × 8 (64 × 9 bits with parity), and 32 × 16 (32 × 18 bits with parity). Mixed-width configurations are also possible, allowing different read and write widths. Table 4–3 summarizes the possible M512 RAM block configurations.

Table 4–3. M512 RAM Block Configurations (Simple Dual-Port RAM)

Read Port	Write Port						
	512 × 1	256 × 2	128 × 4	64 × 8	32 × 16	64 × 9	32 × 18
512 × 1	✓	✓	✓	✓	✓		
256 × 2	✓	✓	✓	✓	✓		
128 × 4	✓	✓	✓		✓		
64 × 8	✓	✓		✓			
32 × 16	✓	✓	✓		✓		
64 × 9						✓	
32 × 18							✓

Figure 4–16. M4K RAM Block Control Signals

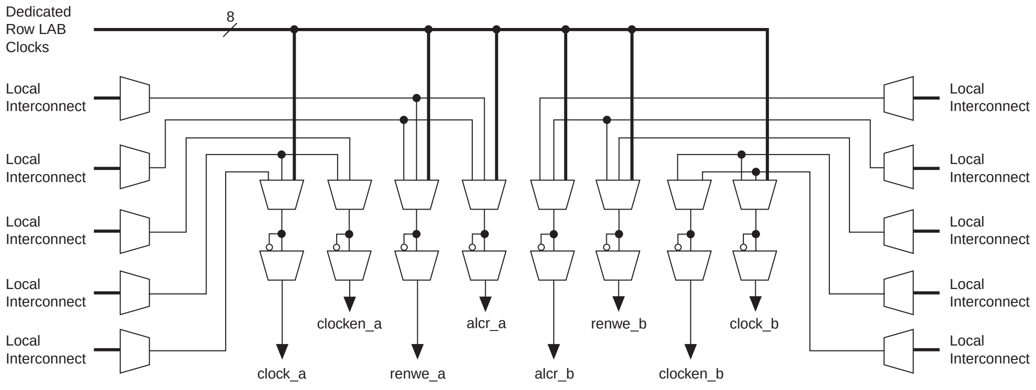
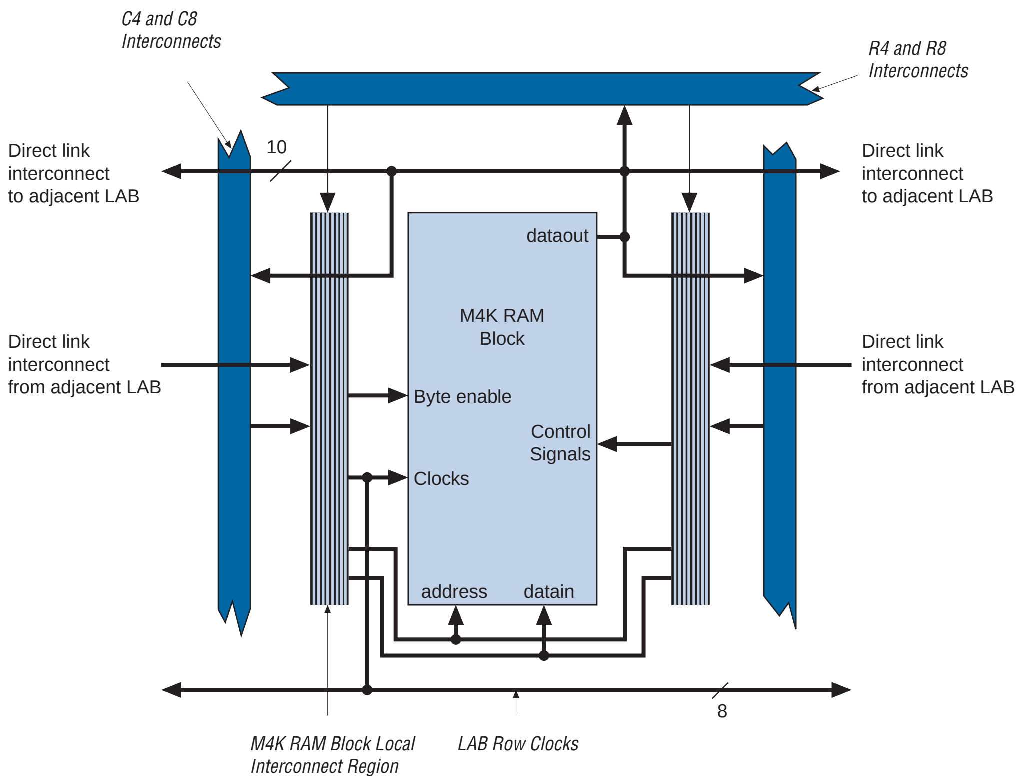


Figure 4–17. M4K RAM Block LAB Row Interface



M-RAM Block

The largest TriMatrix memory block, the M-RAM block, is useful for applications where a large volume of data must be stored on-chip. Each block contains 589,824 RAM bits (including parity bits). The M-RAM block can be configured in the following modes:

- True dual-port RAM
- Simple dual-port RAM
- Single-port RAM
- FIFO RAM

You cannot use an initialization file to initialize the contents of a M-RAM block. All M-RAM block contents power up to an undefined value. Only synchronous operation is supported in the M-RAM block, so all inputs are registered. Output registers can be bypassed. The memory address and output width can be configured as 64K × 8 (or 64K × 9 bits), 32K × 16 (or 32K × 18 bits), 16K × 32 (or 16K × 36 bits), 8K × 64 (or 8K × 72 bits), and 4K × 128 (or 4K × 144 bits). The 4K × 128 configuration is unavailable in true dual-port mode because there are a total of 144 data output drivers in the block. Mixed-width configurations are also possible, allowing different read and write widths. Tables 4–7 and 4–8 summarize the possible M-RAM block configurations:

Table 4–7. M-RAM Block Configurations (Simple Dual-Port)

Read Port	Write Port				
	64K × 9	32K × 18	16K × 36	8K × 72	4K × 144
64K × 9	✓	✓	✓	✓	
32K × 18	✓	✓	✓	✓	
16K × 36	✓	✓	✓	✓	
8K × 72	✓	✓	✓	✓	
4K × 144					✓

Adder/Subtractor/Accumulator

The adder/subtractor/accumulator is the first level of the adder/output block and can be used as an accumulator or as an adder/subtractor.

Adder/Subtractor

Each adder/subtractor/accumulator block can perform addition or subtraction using the `addnsub` independent control signal for each first-level adder in 18 × 18-bit mode. There are two `addnsub[1..0]` signals available in a DSP block for any configuration. For 9 × 9-bit mode, one `addnsub[1..0]` signal controls the top two one-level adders and another `addnsub[1..0]` signal controls the bottom two one-level adders. A high `addnsub` signal indicates addition, and a low signal indicates subtraction. The `addnsub` control signal can be unregistered or registered once or twice when feeding the adder blocks to match data path pipelines.

The `signa` and `signb` signals serve the same function as the multiplier block `signa` and `signb` signals. The only difference is that these signals can be registered up to two times. These signals are tied to the same `signa` and `signb` signals from the multiplier and must be connected to the same clocks and control signals.

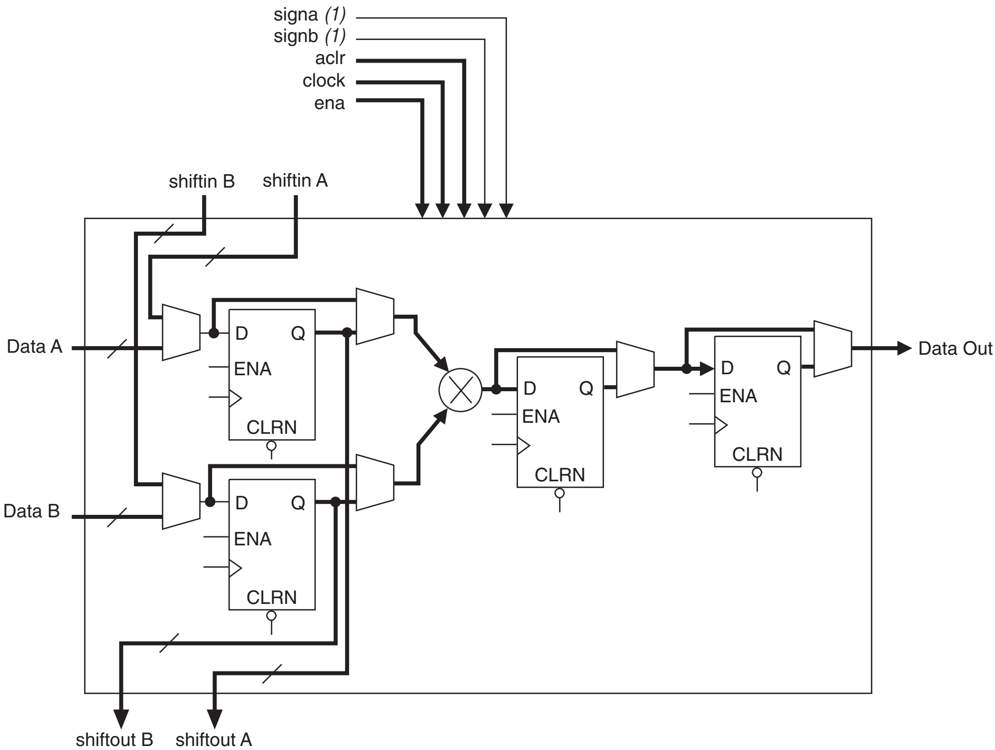
Accumulator

When configured for accumulation, the adder/output block output feeds back to the accumulator as shown in Figure 4–33. The `accum_sload[1..0]` signal synchronously loads the multiplier result to the accumulator output. This signal can be unregistered or registered once or twice. Additionally, the `overflow` signal indicates the accumulator has overflowed or underflowed in accumulation mode. This signal is always registered and must be externally latched in LEs if the design requires a latched `overflow` signal.

Summation

The output of the adder/subtractor/accumulator block feeds to an optional summation block. This block sums the outputs of the DSP block multipliers. In 9 × 9-bit mode, there are two summation blocks providing the sums of two sets of four 9 × 9-bit multipliers. In 18 × 18-bit mode, there is one summation providing the sum of one set of four 18 × 18-bit multipliers.

Figure 4–34. Simple Multiplier Mode



Note to Figure 4–34:

(1) These signals are not registered or registered once to match the data path pipeline.

DSP blocks can also implement one 36 × 36-bit multiplier in multiplier mode. DSP blocks use four 18 × 18-bit multipliers combined with dedicated adder and internal shift circuitry to achieve 36-bit multiplication. The input shift register feature is not available for the 36 × 36-bit multiplier. In 36 × 36-bit mode, the device can use the register that is normally a multiplier-result-output register as a pipeline stage for the 36 × 36-bit multiplier. Figure 4–35 shows the 36 × 36-bit multiply mode.

Clock Multiplication & Division

Each Stratix GX device enhanced PLL provides clock synthesis for PLL output ports using $m/(n \times$ post-scale counter) scaling factors. The input clock is divided by a pre-scale divider, n, and is then multiplied by the m feedback factor. The control loop drives the VCO to match $f_{IN} \times (m/n)$. Each output port has a unique post-scale counter that divides down the high-frequency VCO. For multiple PLL outputs with different frequencies, the VCO is set to the least common multiple of the output frequencies that meets its frequency specifications. Then, the post-scale dividers scale down the output frequency for each output port. For example, if output frequencies required from one PLL are 33 and 66 MHz, set the VCO to 330 MHz (the least common multiple in the VCO's range). There is one pre-scale divider, n, and one multiply divider, m, per PLL, with a range of 1 to 512 on each. There are two post-scale dividers (l) for regional clock output ports, four counters (g) for global clock output ports, and up to four counters (e) for external clock outputs, all ranging from 1 to 512. The Quartus II software automatically chooses the appropriate scaling factors according to the input frequency, multiplication, and division values entered.

Clock Switchover

To effectively develop high-reliability network systems, clocking schemes must support multiple clocks to provide redundancy. For this reason, Stratix GX device enhanced PLLs support a flexible clock switchover capability. Figure 4–52 shows a block diagram of the switchover circuit.The switchover circuit is configurable, so you can define how to implement it. Clock-sense circuitry automatically switches from the primary to secondary clock for PLL reference when the primary clock signal is not present.

pin. The I/O standards supported by any particular bank determines what standards are possible for an external clock output driven by the fast PLL in that bank.

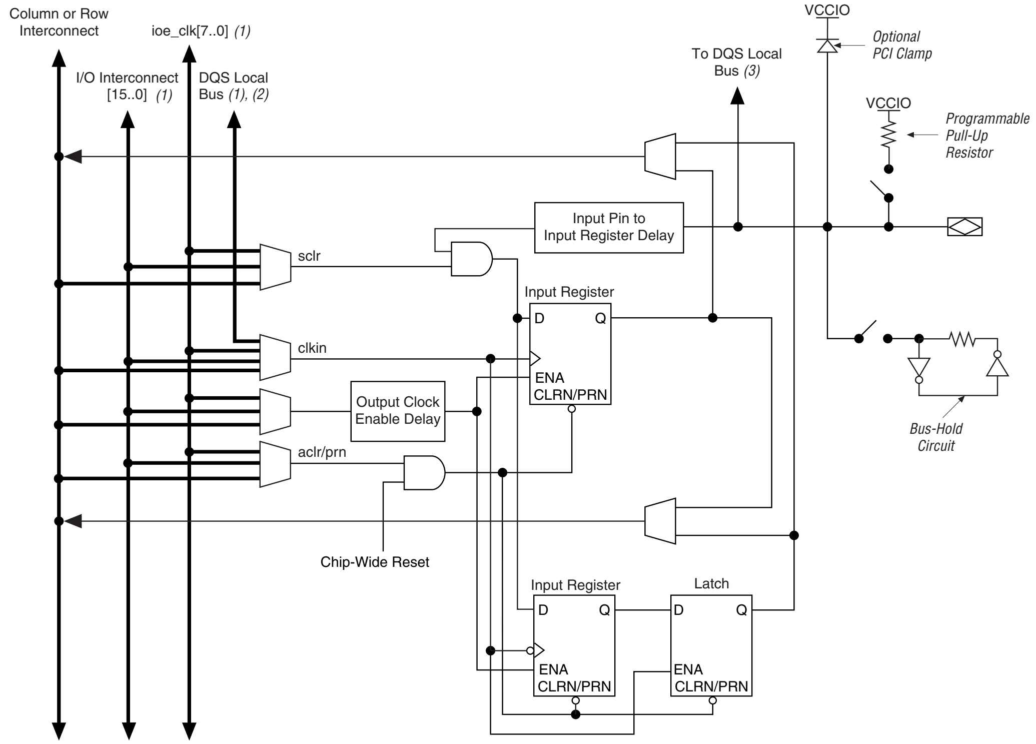
Table 4–20 shows the I/O standards supported by fast PLL input pins.

Table 4–20. Fast PLL Port Input Pin I/O Standards

I/O Standard	Input	
	INCLK	PLLENABLE
LVTTL	✓	✓
LVCMOS	✓	✓
2.5 V	✓	
1.8 V	✓	
1.5 V	✓	
3.3-V PCI		
3.3-V PCI-X		
LVPECL	✓	
3.3-V PCML	✓	
LVDS	✓	
HyperTransport technology	✓	
Differential HSTL	✓	
Differential SSTL		
3.3-V GTL	✓	
3.3-V GTL+	✓	
1.5V HSTL class I	✓	
1.5V HSTL class II	✓	
SSTL-18 class I	✓	
SSTL-18 class II	✓	
SSTL-2 class I	✓	
SSTL-2 class II	✓	
SSTL-3 class I	✓	
SSTL-3 class II	✓	
AGP (1× and 2×)	✓	
CTT	✓	

When using the IOE for DDR inputs, the two input registers clock double rate input data on alternating edges. An input latch is also used within the IOE for DDR input acquisition. The latch holds the data that is present during the clock high times. This allows both bits of data to be synchronous with the same clock edge (either rising or falling). Figure 4–64 shows an IOE configured for DDR input. Figure 4–65 shows the DDR input timing diagram.

Figure 4–64. Stratix GX IOE in DDR Input I/O Configuration *Note (1)*



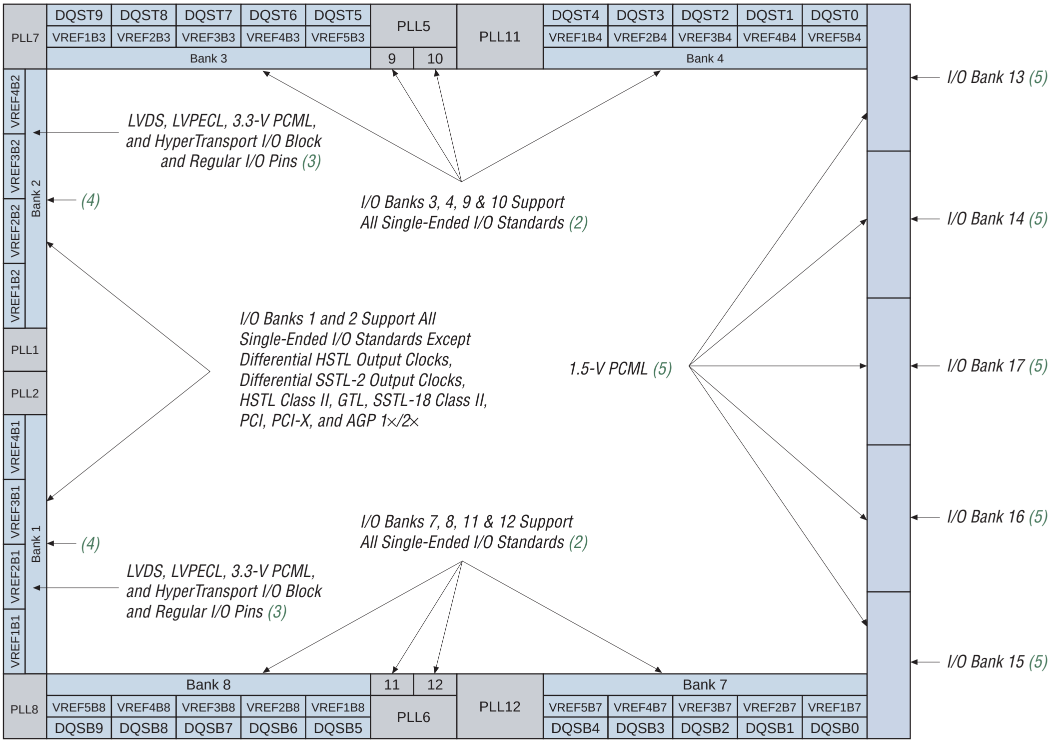
Notes to Figure 4–64:

(1) All input signals to the IOE can be inverted at the IOE.

(2) This signal connection is only allowed on dedicated DQ function pins.

(3) This signal is for dedicated DQS function pins only.

Figure 4–69. Stratix GX I/O Banks *Notes (1), (2), (3)*



Notes to Figure 4–69:

(1) Figure 4–69 is a top view of the Stratix GX silicon die.

(2) Banks 9 through 12 are enhanced PLL external clock output banks.

(3) If the high-speed differential I/O pins are not used for high-speed differential signaling, they can support all of the I/O standards except HSTL class I and II, GTL, SSTL-18 Class II, PCI, PCI-X, and AGP 1×/2×.

(4) For guidelines for placing single-ended I/O pads next to differential I/O pads, see the *Selectable I/O Standards in Stratix & Stratix GX Devices* chapter in the *Stratix GX Device Handbook, Volume 2*.

(5) These I/O banks in Stratix GX devices also support the LVDS, LVPECL, and 3.3-V PCML I/O standards on reference clocks and receiver input pins (AC coupled)

Table 4–33. Stratix GX JTAG Instructions (Part 2 of 2)	
JTAG Instruction	**Description**
CLAMP *(1)*	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding I/O pins to a state defined by the data in the boundary-scan register.
ICR instructions	Used when configuring a Stratix GX device through the JTAG port with a MasterBlaster™ or ByteBlasterMV™ download cable, or when using a .jam file or .jbc file with an embedded processor.
PULSE_NCONFIG	Emulates pulsing the nCONFIG pin low to trigger reconfiguration even though the physical pin is unaffected.
CONFIG_IO	Allows the IOE standards to be configured through the JTAG chain. Stops configuration if executed during configuration. Can be executed before or after configuration.
SignalTap instructions	Monitors internal device operation with the SignalTap embedded logic analyzer.

Note to Table 4–33:

(1) Bus hold and weak pull-up resistor features override the high-impedance state of HIGHZ, CLAMP, and EXTEST.

The Stratix GX device instruction register length is 10 bits, and the USERCODE register length is 32 bits. Tables 4–34 and 4–35 show the boundary-scan register length and IDCODE information for Stratix GX devices.

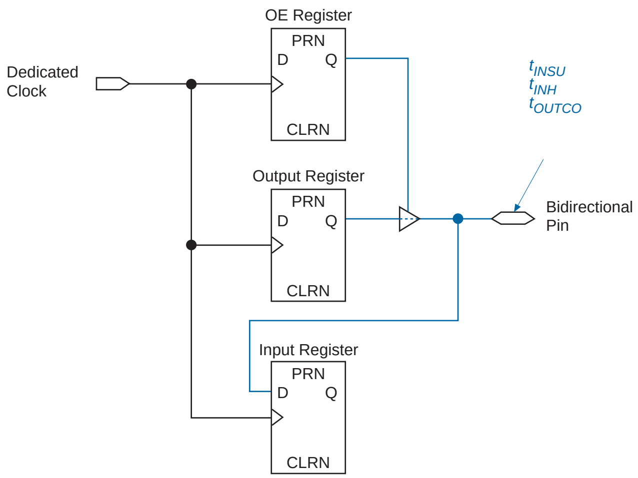
Table 4–34. Stratix GX Boundary-Scan Register Length

Device	Boundary-Scan Register Length
EP1SGX10	1,029
EP1SGX25	1,665
EP1SGX40	1,941

Table 4–35. 32-Bit Stratix GX Device IDCODE (Part 1 of 2)

Device	IDCODE (32 Bits) *(1)*			
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer Identity (11 Bits)	LSB (1 Bit) *(2)*
EP1SGX10	0000	0010 0000 0100 0001	000 0110 1110	1
EP1SGX25	0000	0010 0000 0100 0011	000 0110 1110	1

Figure 6–6. External Timing in Stratix GX Devices



All external I/O timing parameters shown are for 3.3-V LVTTL or LVCMOS I/O standards with the maximum current strength. For external I/O timing using standards other than LVTTL or LVCMOS use the I/O standard input and output delay adders in Tables 6–72 through 6–76.

Table 6–51 shows the external I/O timing parameters when using fast regional clock networks.

Table 6–51. Stratix GX Fast Regional Clock External I/O Timing Parameters *Notes (1), (2)*

Symbol	Parameter	Conditions
t_{INSU}	Setup time for input or bidirectional pin using column IOE input register with fast regional clock fed by `FCLK` pin	
t_{INH}	Hold time for input or bidirectional pin using column IOE input register with fast regional clock fed by `FCLK` pin	
t_{OUTCO}	Clock-to-output delay output or bidirectional pin using column IOE output register with fast regional clock fed by `FCLK` pin	C_{LOAD} = 10 pF

Notes to Table 6–51:
(1) These timing parameters are sample-tested only.
(2) These timing parameters are for column IOE pins. Row IOE pins are 100- to 250-ps slower depending on device and speed grade and whether it is t_{CO} or t_{SU}. You should use the Quartus II software to verify the external timing for any pin.

The scaling factors for output pin timing in Table 6–80 are shown in units of time per pF unit of capacitance (ps/pF). Add this delay to the combinational timing path for output or bidirectional pins in addition to the "I/O Adder" delays shown in Tables 6–72 through 6–77 and the "IOE Programmable Delays" in Tables 6–78 and 6–79.

Table 6–80. Output Delay Adder for Loading on LVTTL/LVCMOS Output Buffers

LVTTL/LVCMOS Standards						
Conditions		**Output Pin Adder Delay (ps/pF)**				
Parameter	**Value**	3.3-V LVTTL	2.5-V LVTTL	1.8-V LVTTL	1.5-V LVTTL	LVCMOS
Drive Strength	24 mA	15	–	–	-	8
	16 mA	25	18	–	–	–
	12 mA	30	25	25	–	15
	8 mA	50	35	40	35	20
	4 mA	60	–	–	80	30
	2 mA	–	75	120	160	60
SSTL/HSTL Standards						
Conditions		**Output Pin Adder Delay (ps/pF)**				
		SSTL-3	SSTL-2	SSTL-1.8	1.5-V HSTL	1.8-V HSTL
Class I		25	25	25	25	25
Class II		25	20	25	20	20
GTL+/GTL/CTT/PCI Standards						
Conditions		**Output Pin Adder Delay (ps/pF)**				
Parameter	**Value**	GTL+	GTL	CTT	PCI	AGP
V_{CCIO} voltage level	3.3 V	18	18	25	20	20
	2.5 V	15	18	-	-	-